



What We Know and Do Not Know About Cryogenic HFET's

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Outline

- **Short history of cryogenic FETs**
- **Theory and experiment: examples of amplifiers (1989-2008)**
- **On minimum noise measure of InP HFETs**
- **Things we still do not know**
- **Where do we go from here?**
 - ❖ **New devices**
 - ❖ **Not so cold receivers**
 - ❖ **Very broadband receivers**



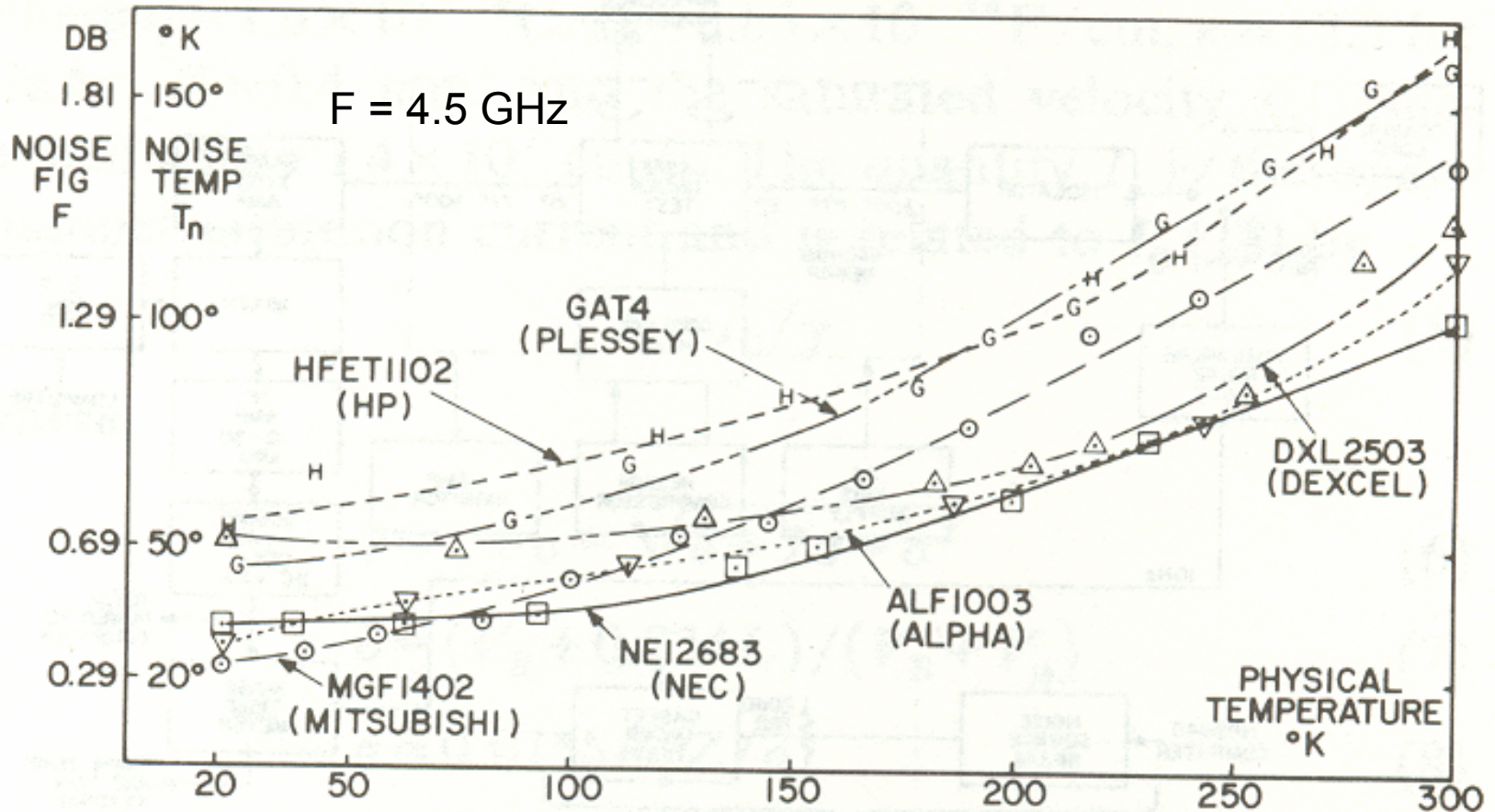
Cryogenic Experiments

- 1970 – First cryogenic experiments, Lorigou *et al* (France NTC), 120 K at 1 GHz L-band
- 1976 – Cryogenic experiments at X-band ,Liechti *et al.* (HP), 60 K at 12 GHz 1980
- 1980 – Practical cryogenic amplifiers using MESFET's demonstrated, Weinreb *et al.* (NRAO), 8 K at 1.5 GHz, 20 K at 5 GHz
- 1984 – GaAs/AlGaAs HFET at cryogenic temperatures, Pospieszalski, Weinreb (NRAO), 10 K at 8.4 GHz
- 1988 – PHEMT cooled, Weinreb *et al.* (NRAO), 25 K at 40 GHz
- 1989 – FET noise model suitable for CAD of cryogenic amplifiers
- 1993 – Evaluation of InP HFET's at cryogenic temperatures, Pospieszalski *et al.* (NRAO), 10 K at 40 GHz



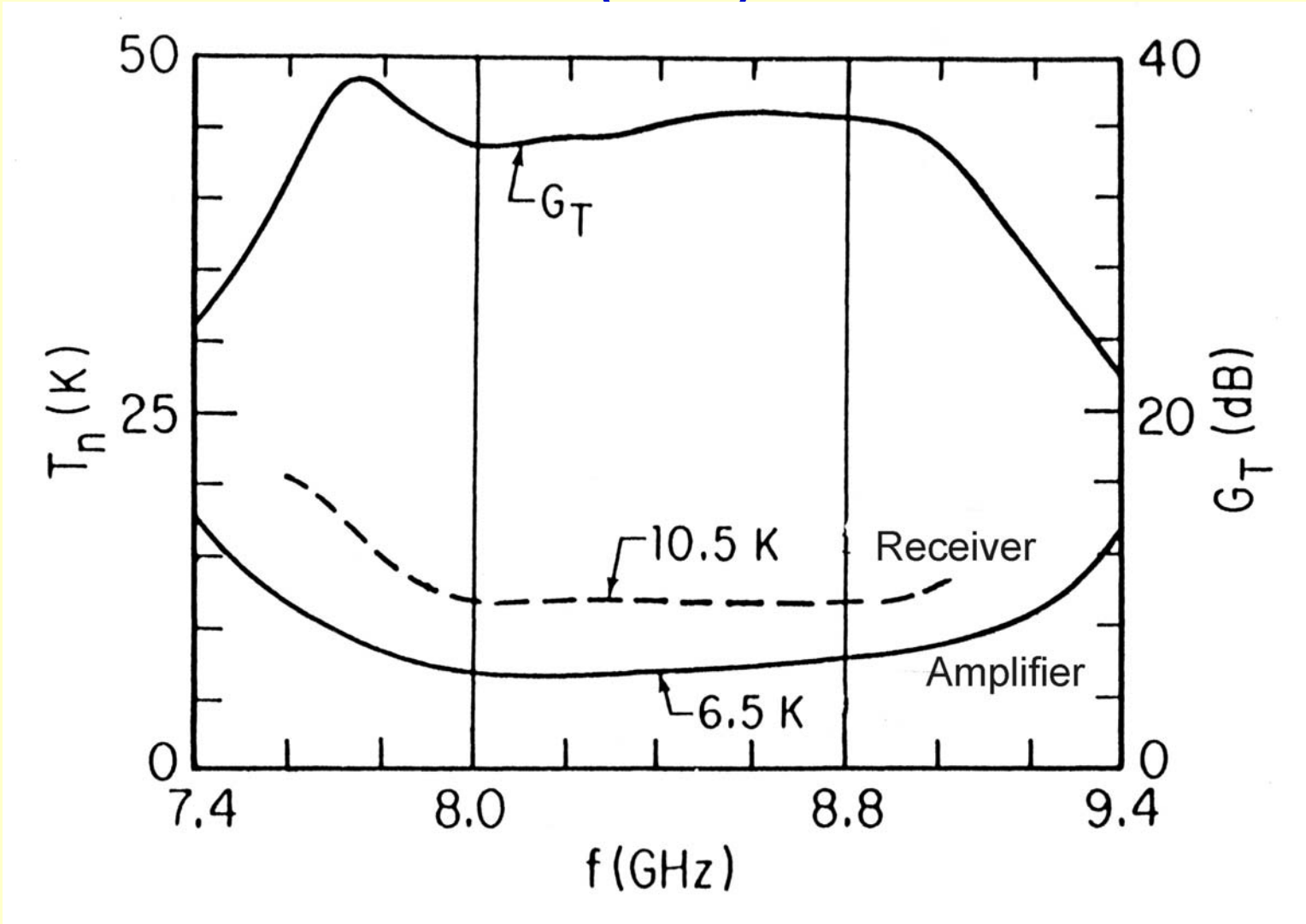
Evaluation of Different MESFET's

S.Weinreb (1980)

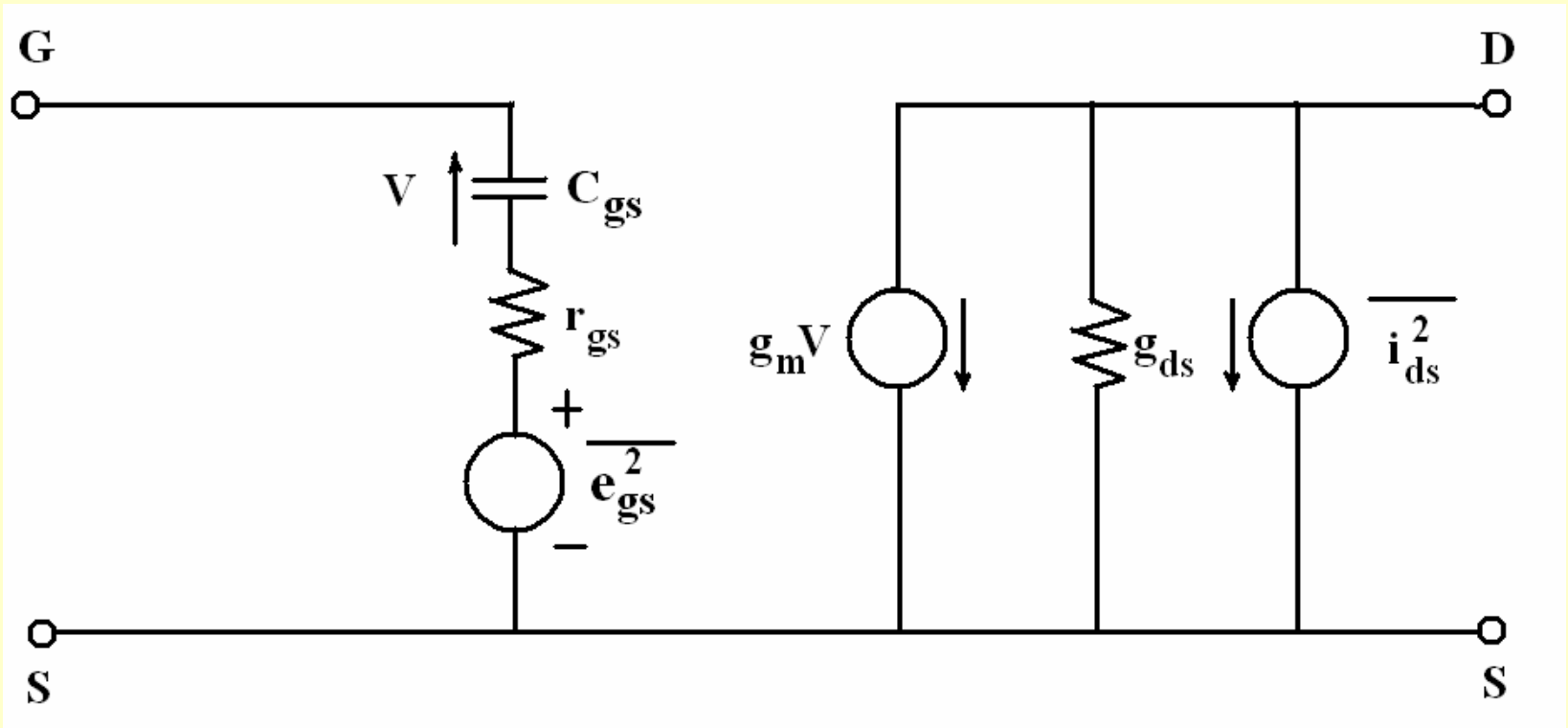




V-N Receiver and Amplifier with GE HFET's, (1987)



Simplest Noise Equivalent Circuit of a FET (1988)



$$\overline{e_{gs}^2} = 4kT_g r_{gs} \Delta f$$

$$\overline{i_{ds}^2} = 4kT_d g_{ds} \Delta f$$



Noise Parameters of Intrinsic Chip – Approximation

For: $\frac{f}{f_t} \ll \sqrt{\frac{T_g}{T_d} \frac{1}{r_{gs} g_{ds}}}$

$$T_{\min} \cong 2 \frac{f}{f_t} \sqrt{g_{ds} T_d r_{gs} T_g}$$

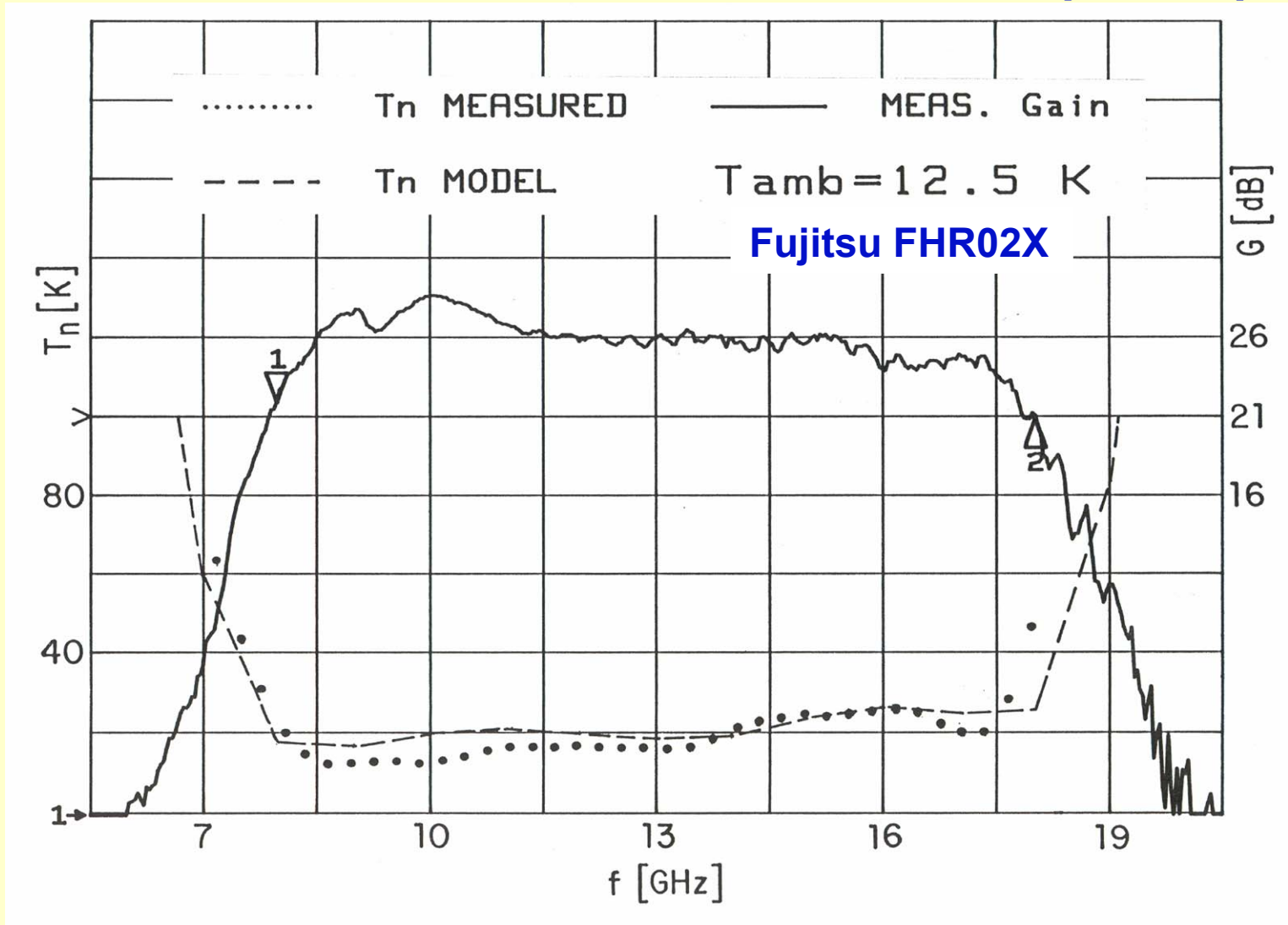
$$f_t = \frac{g_m}{2 \pi C_{gs}}$$

$$T_{\min} \approx \frac{f}{f_{\max}} \sqrt{T_g T_d}$$

$$f_{\max} = f_t \sqrt{\frac{1}{4 g_{ds} r_{gs}}}$$

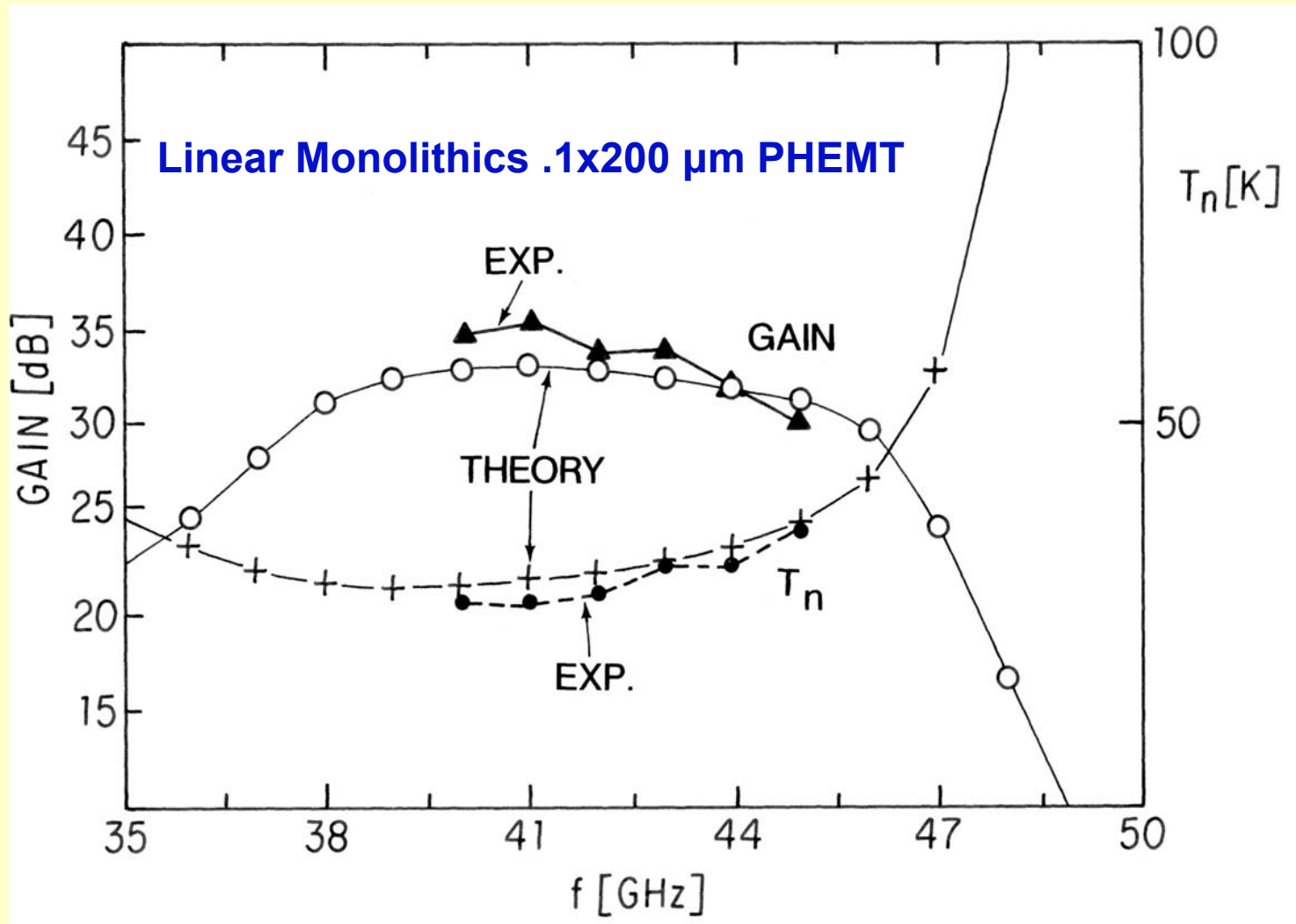


8-18 GHz Amplifier at 12.5 K (1988)



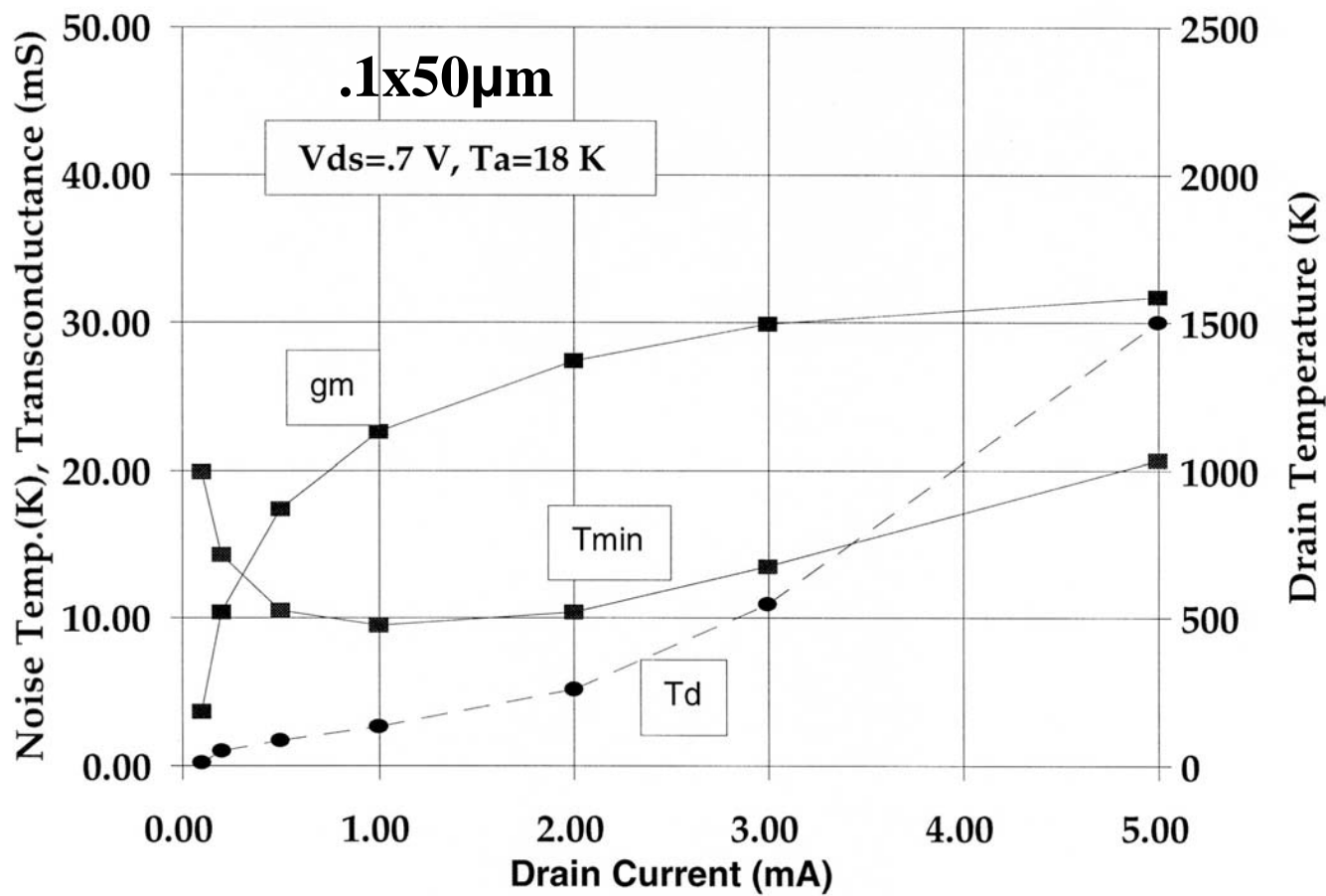


VLBA 40- 45 GHz Amplifier (1990)





Optimal Noise Bias of InP HFET at 18 K (1993)

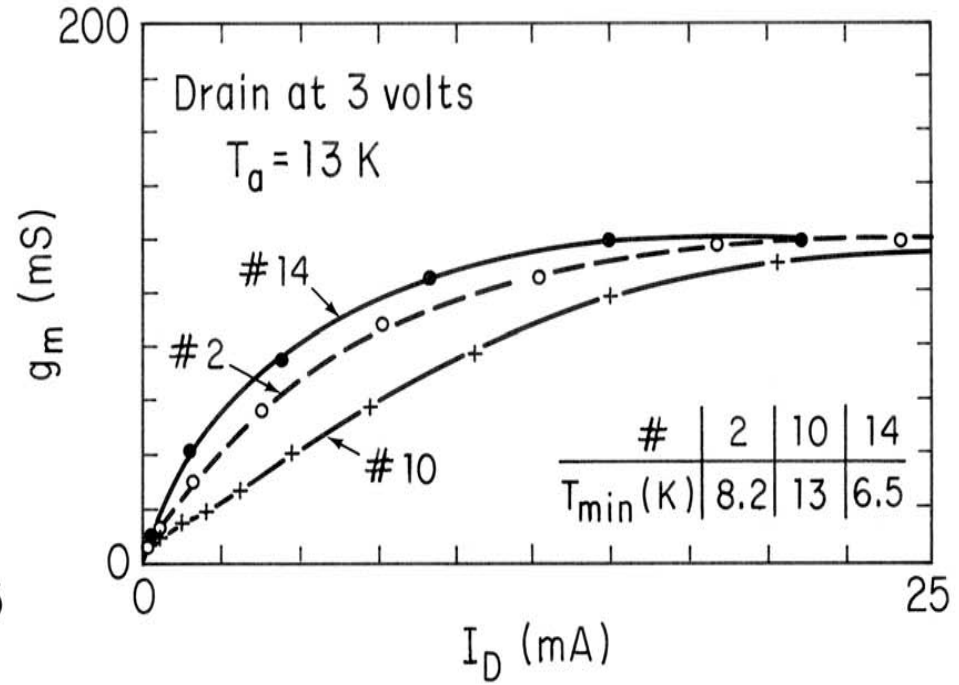
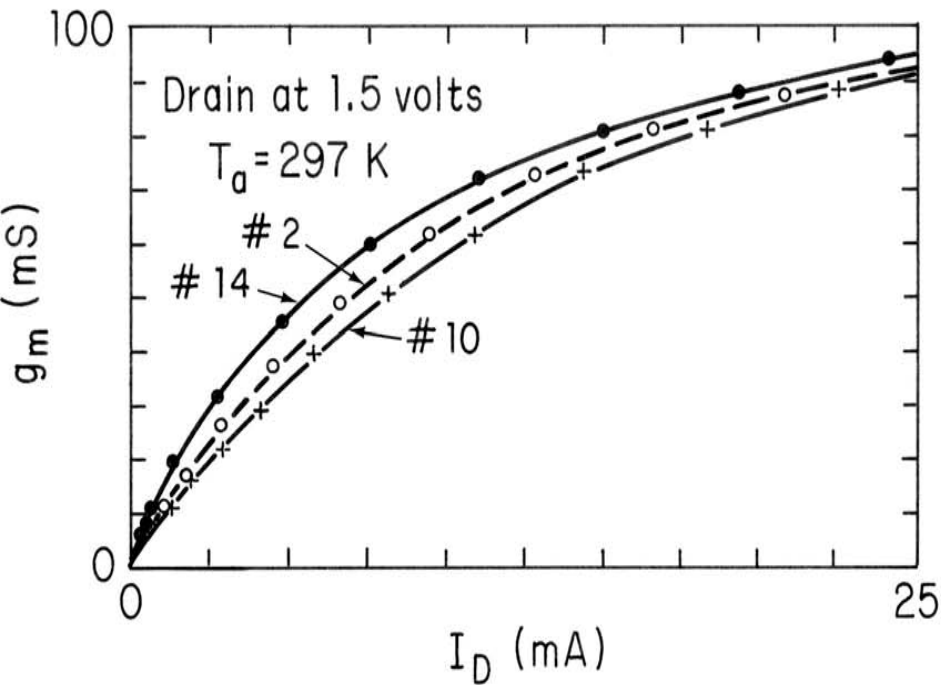


Optimal bias minimizes the value of:

$$f(V_{ds}, I_{ds}) \approx \frac{\sqrt{T_d g_{ds}}}{f_t} \approx \frac{\sqrt{I_D}}{g_m}$$



Cryogenic T_{\min} at 8.4 GHz and DC Pinch-off Characteristics of GE HFET's (1987)

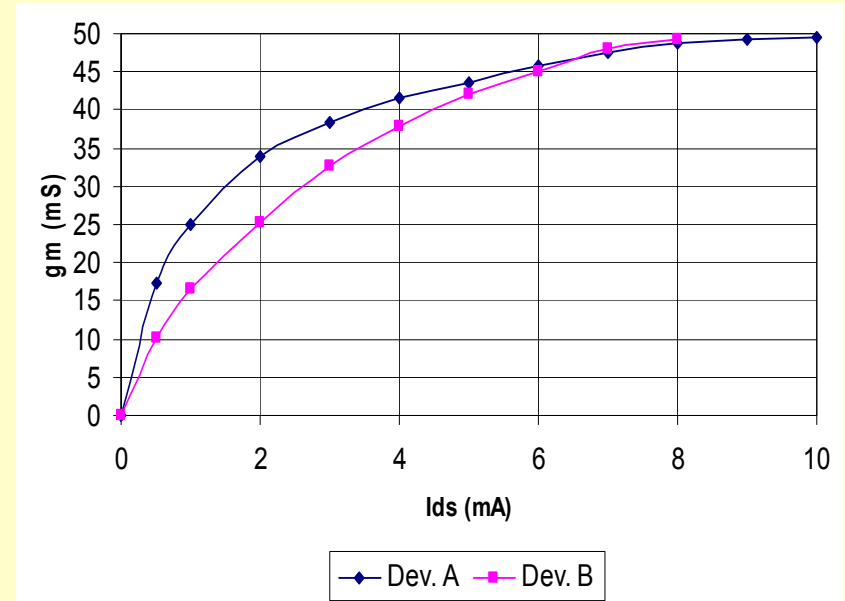
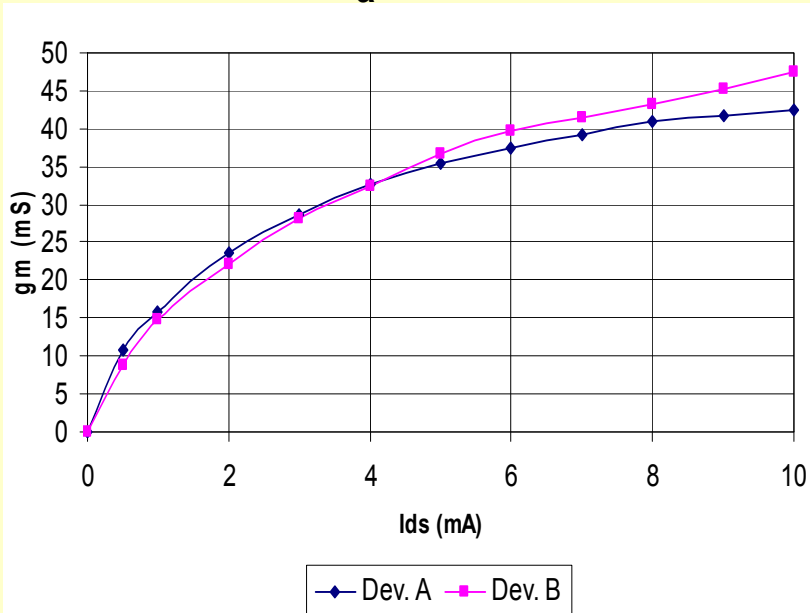




Example of “poor pinch off” InP HFET (1993)

$T_a=297\text{ K}$

$T_a=18\text{ K}$



$T_{min}(297\text{ K})$

$T_{min}(18\text{ K})$

at 40 GHz

Dev. A

148

12

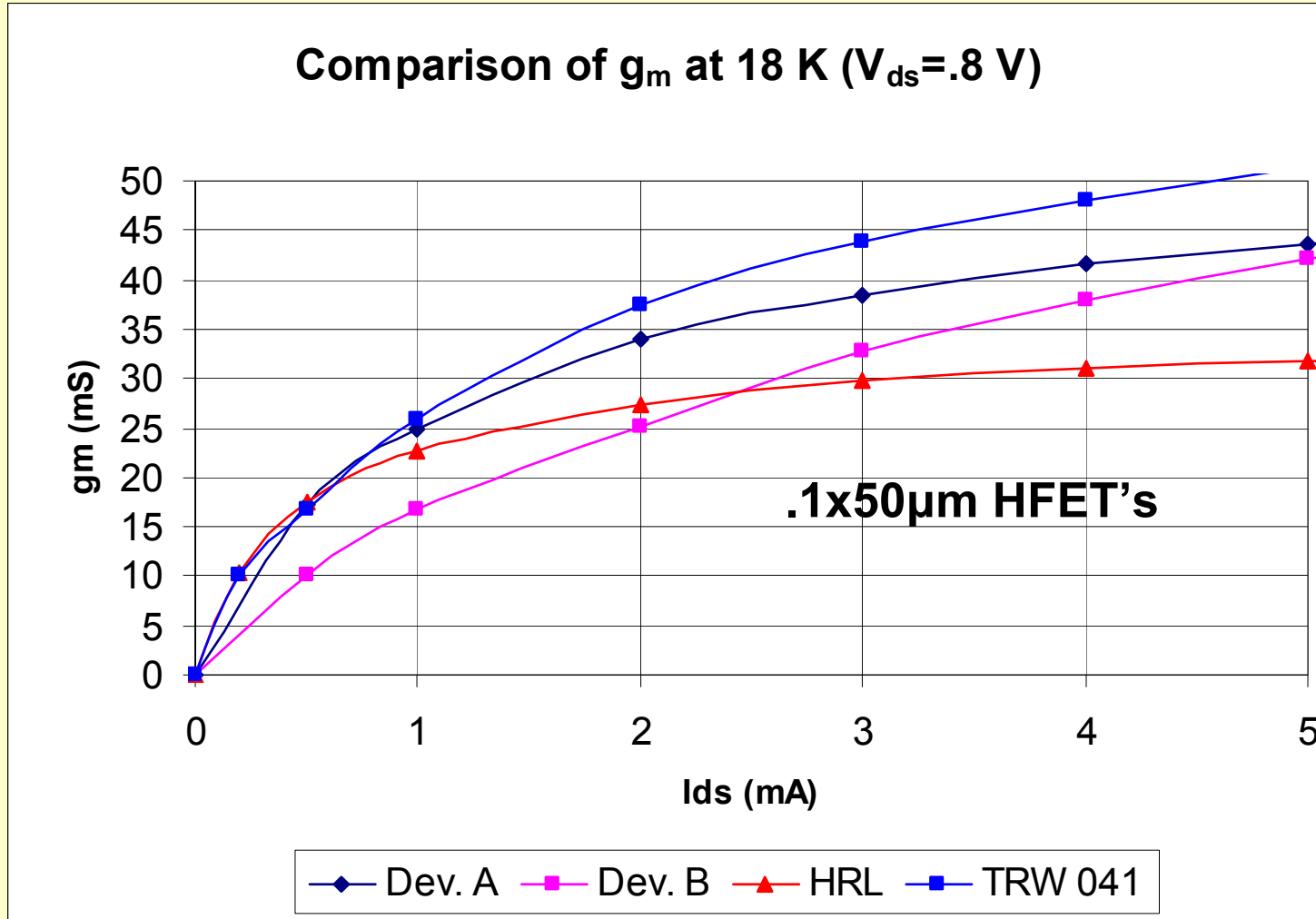
Dev. B

134

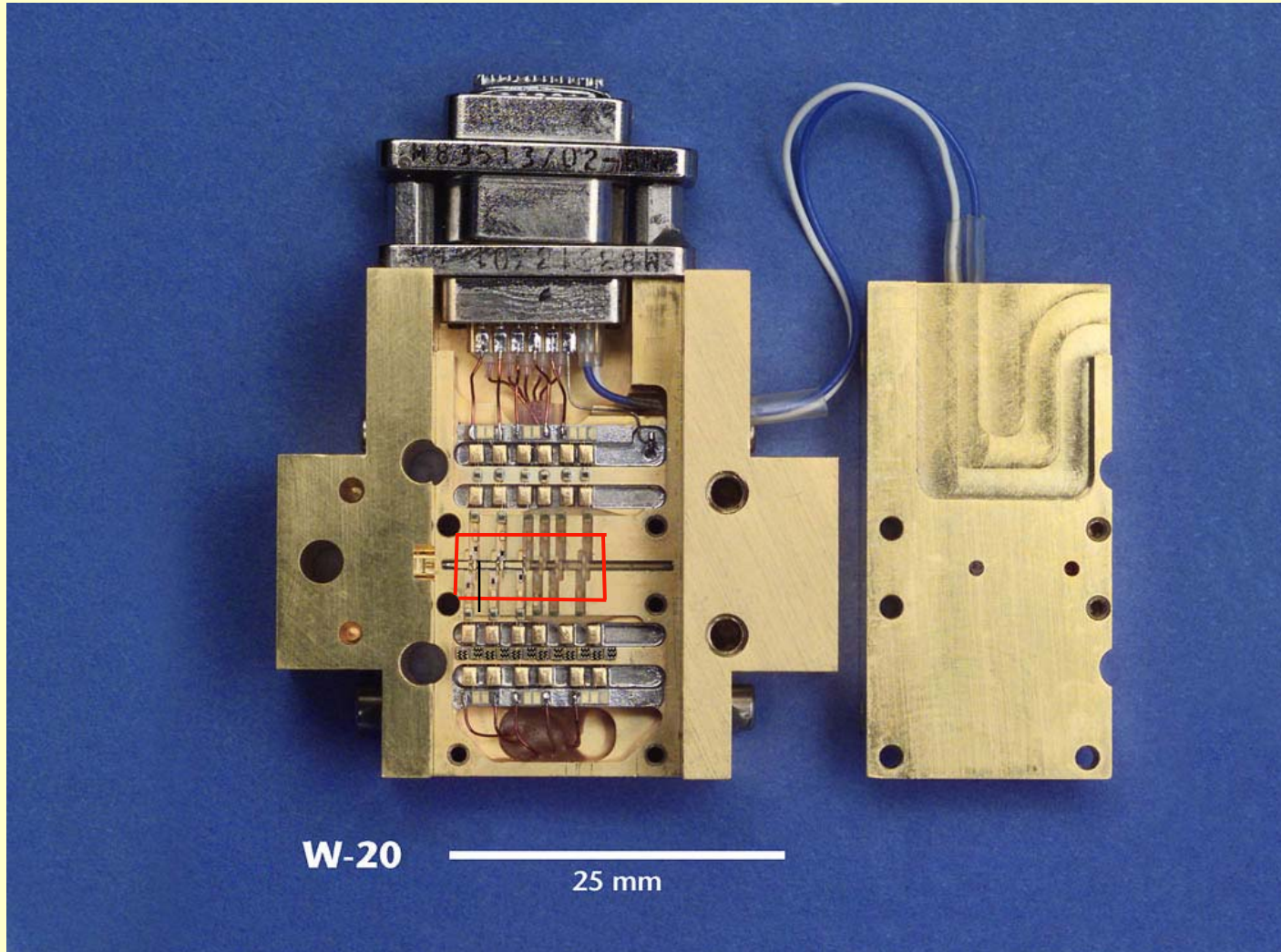
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Comparison of GE/MM, HRL and TRW HFET's

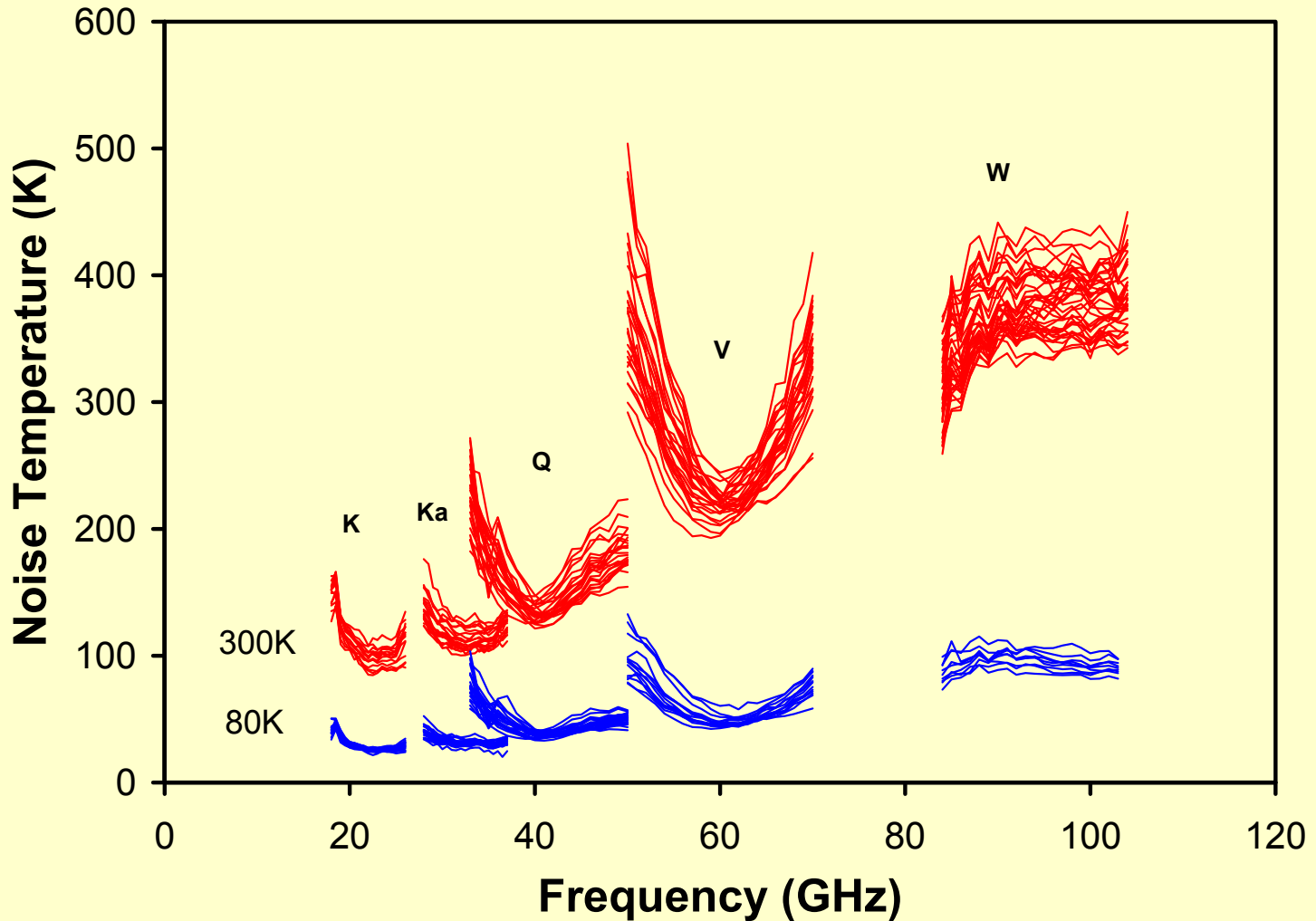


MAP Amplifier: W-Band (1998)



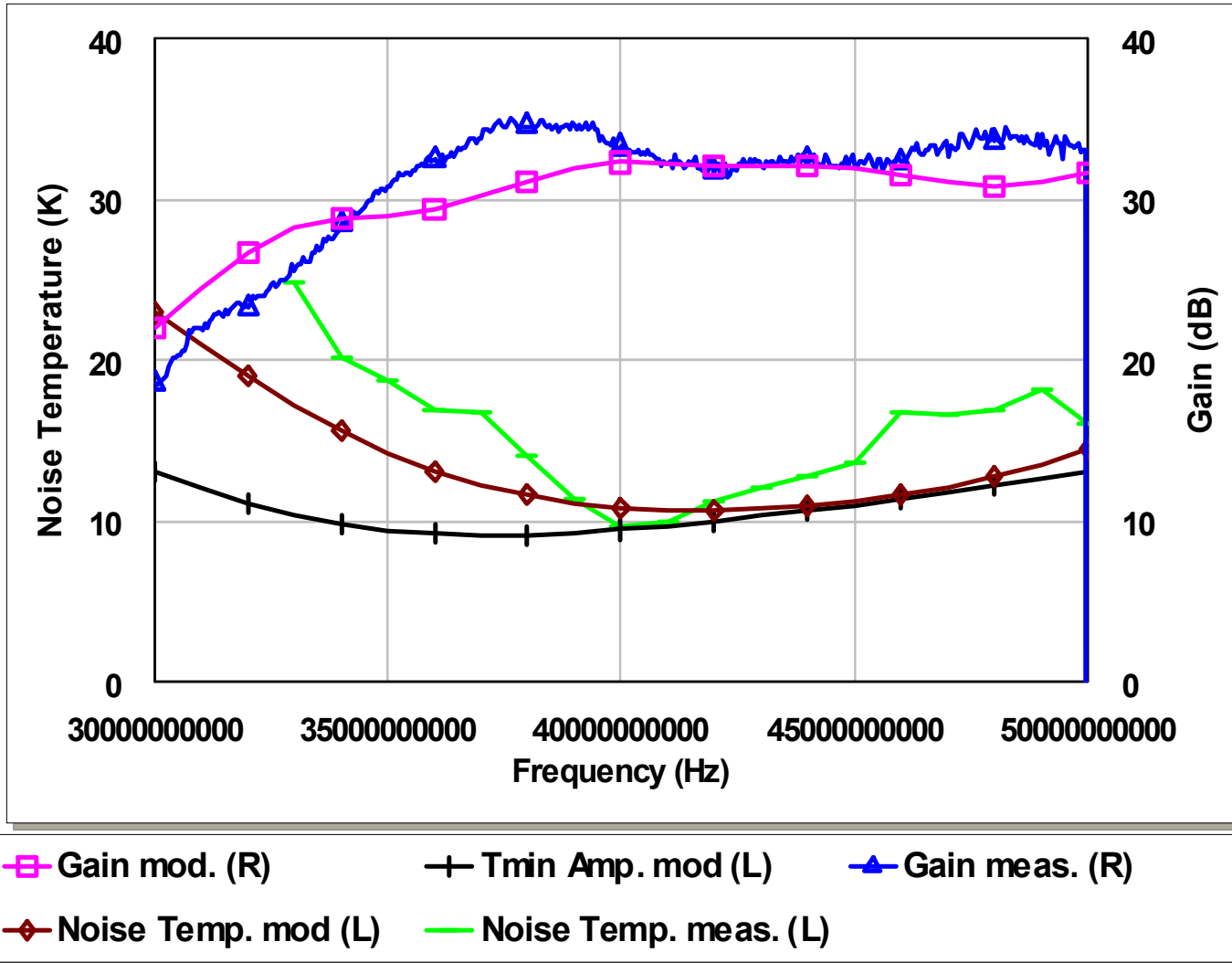


MAP Amplifier: Noise Temperature



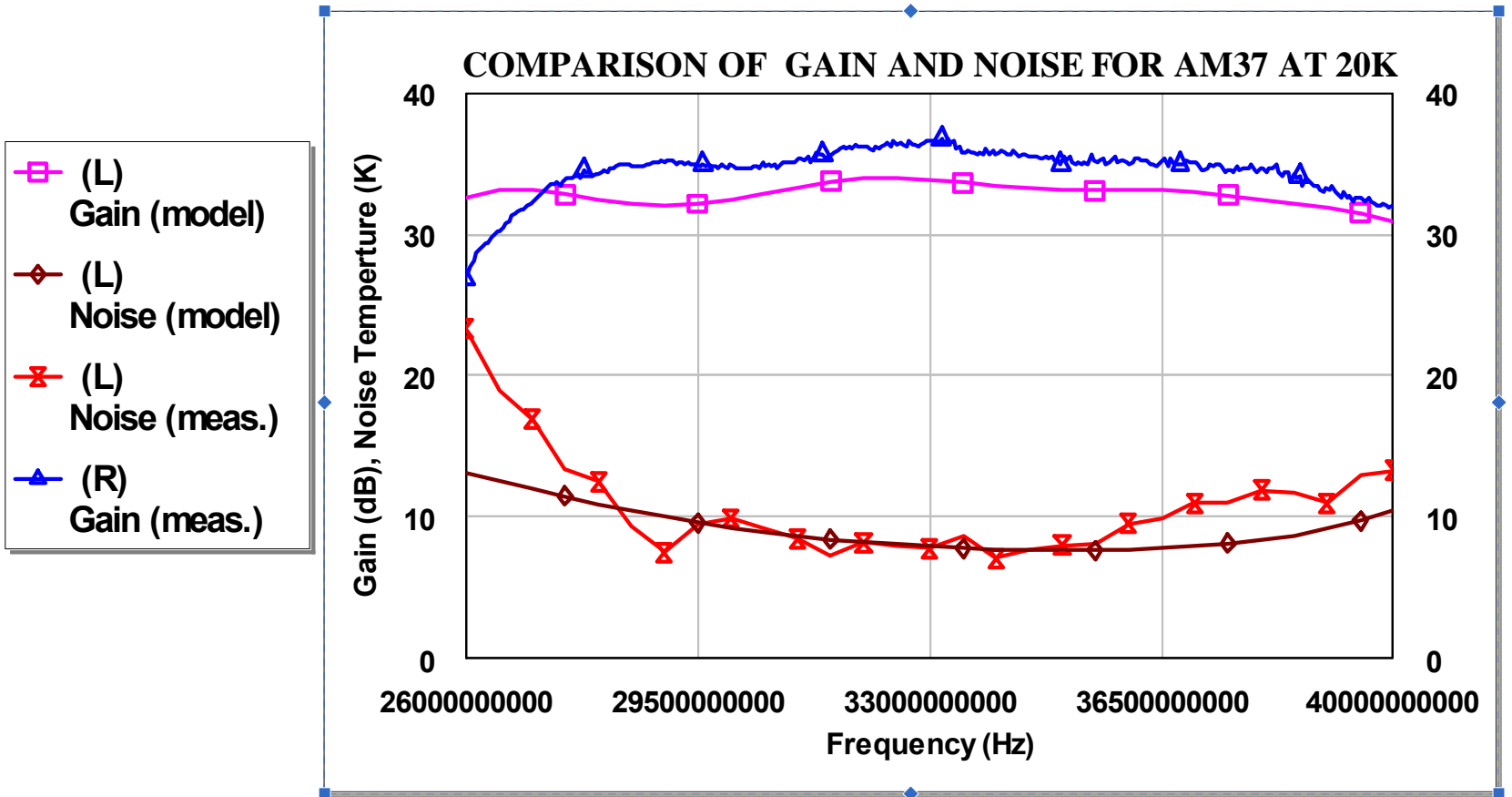


40-50 GHz Amplifier at 15 K



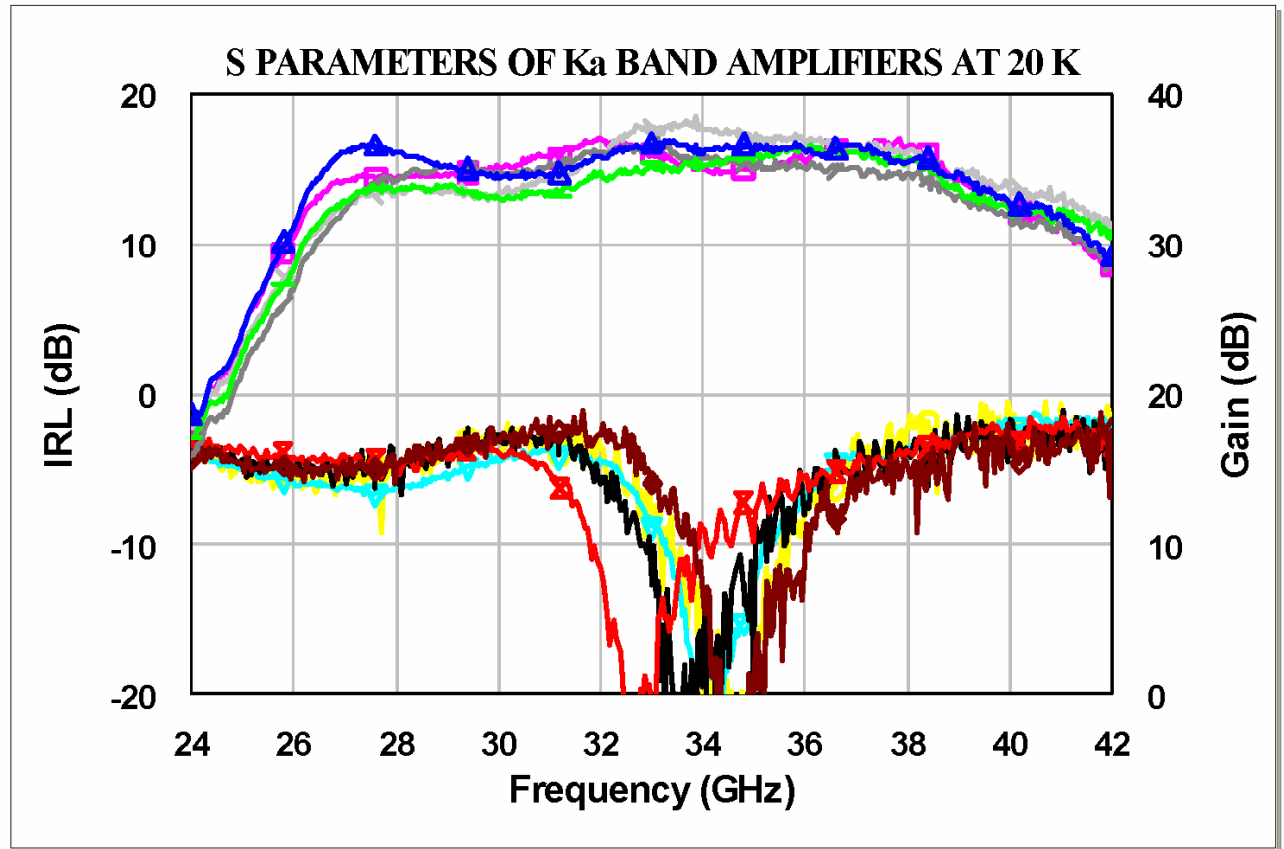
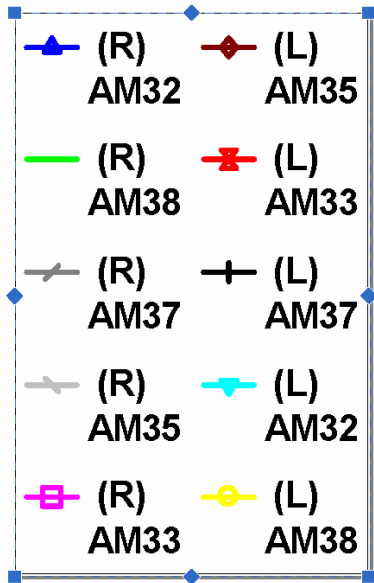


EVLA K_a Band Amplifier



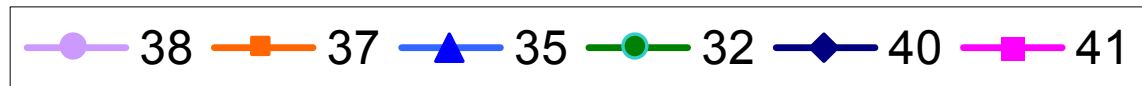
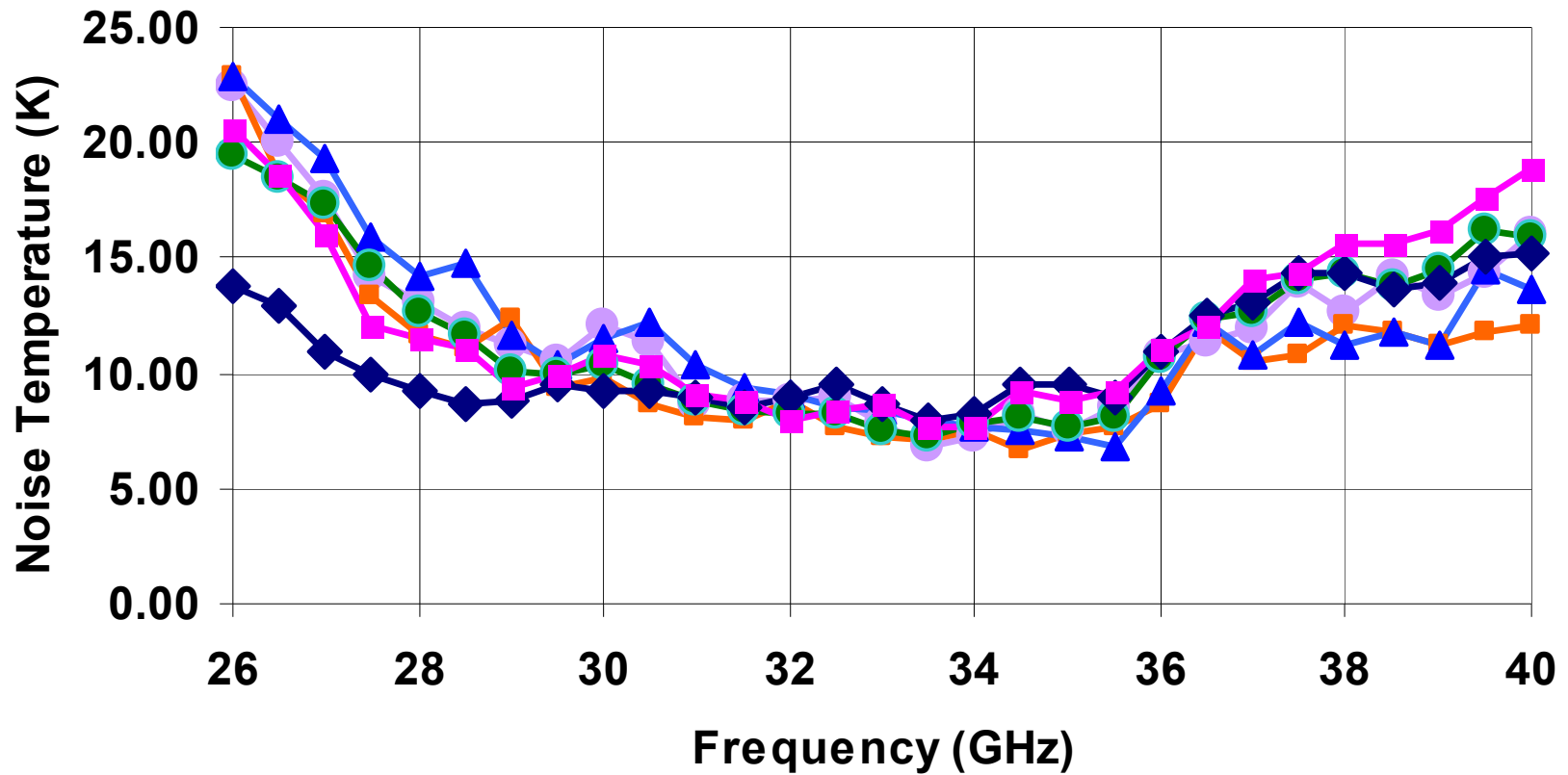


EVLA K_a Band Amplifier

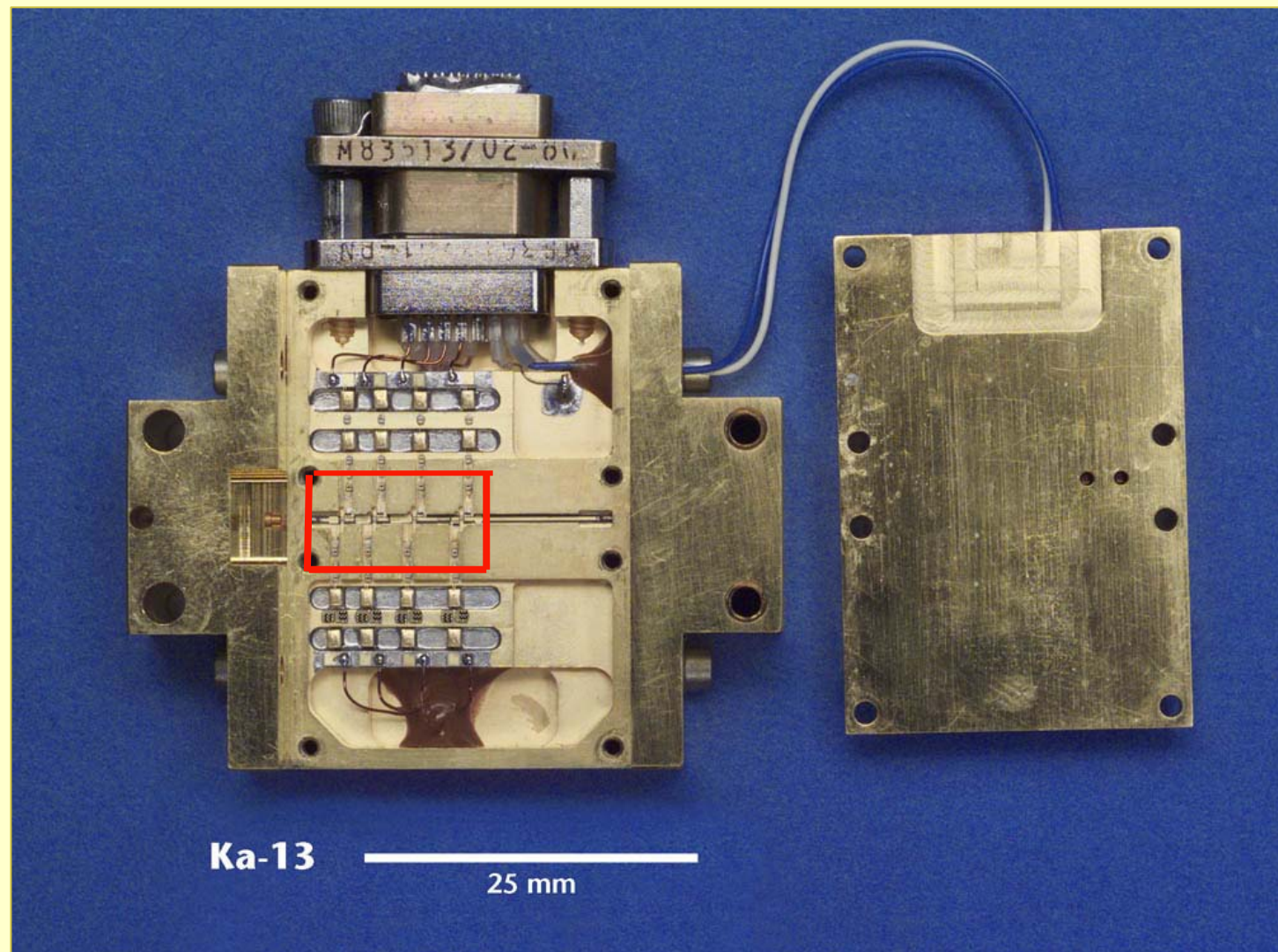




EVLA K_a -Band Amplifiers at 19 K

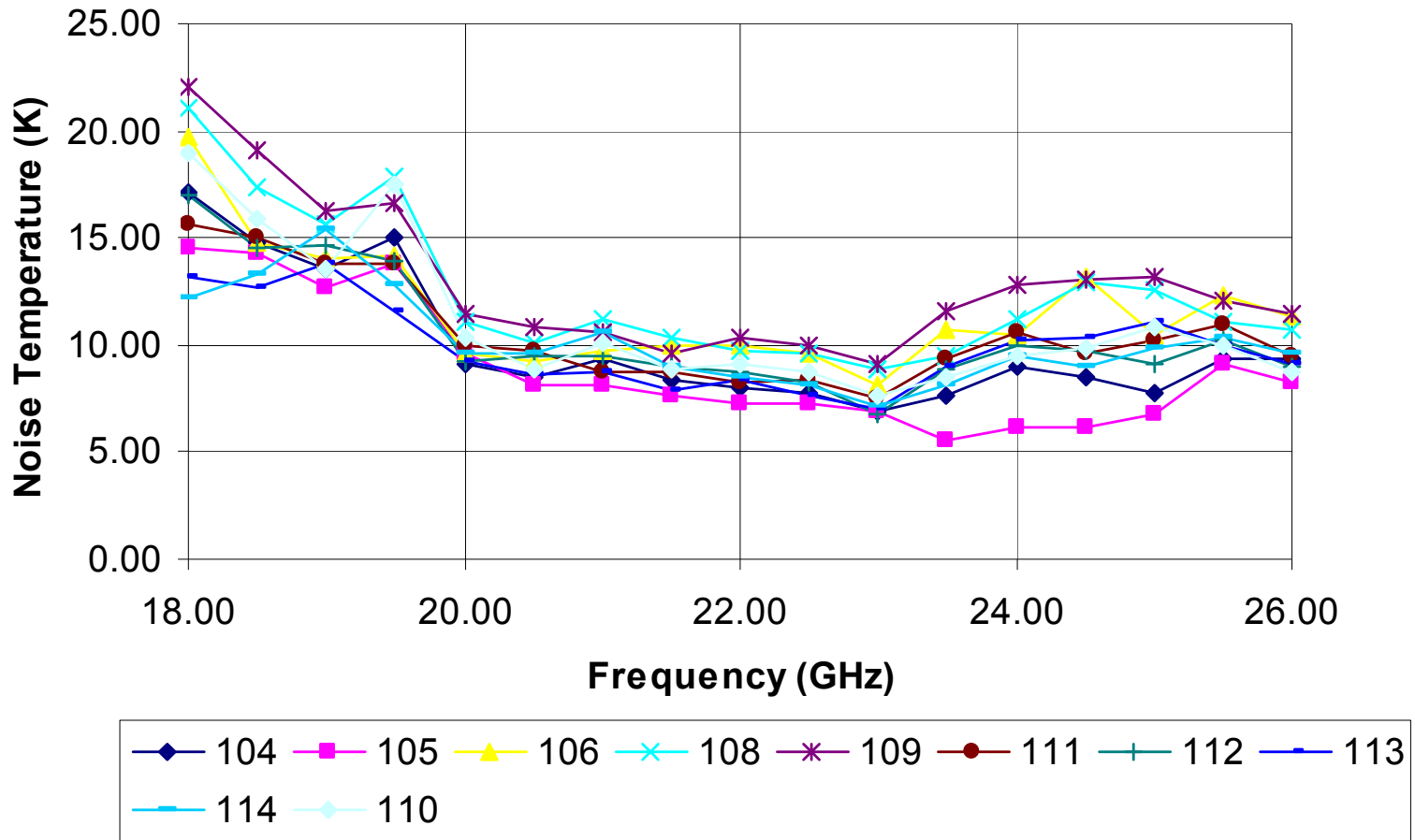


EVLA Ka Band Amplifier



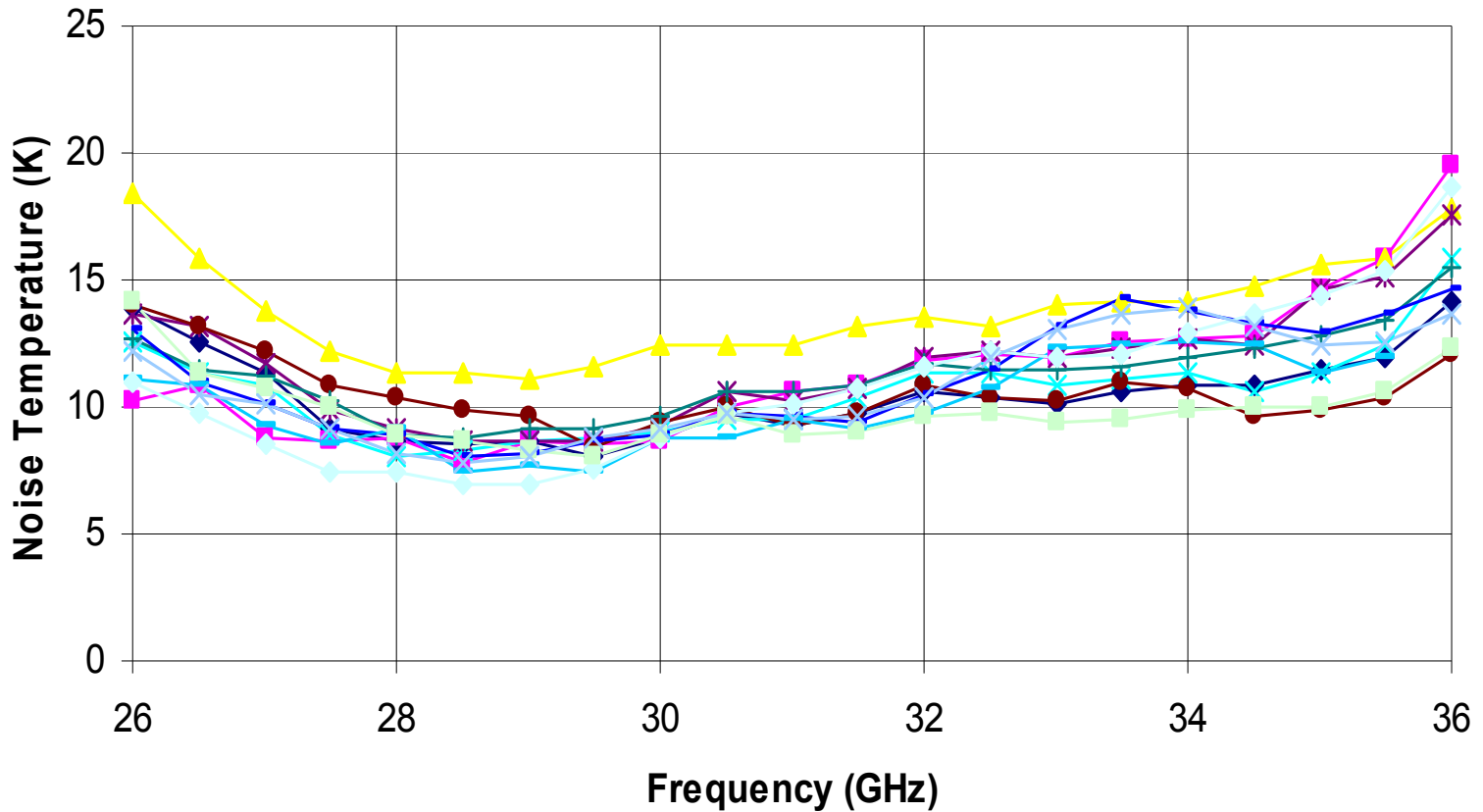


EVLA K-BAND AMPLIFIERS WITH CRYO3 DEVICES AT 19 K



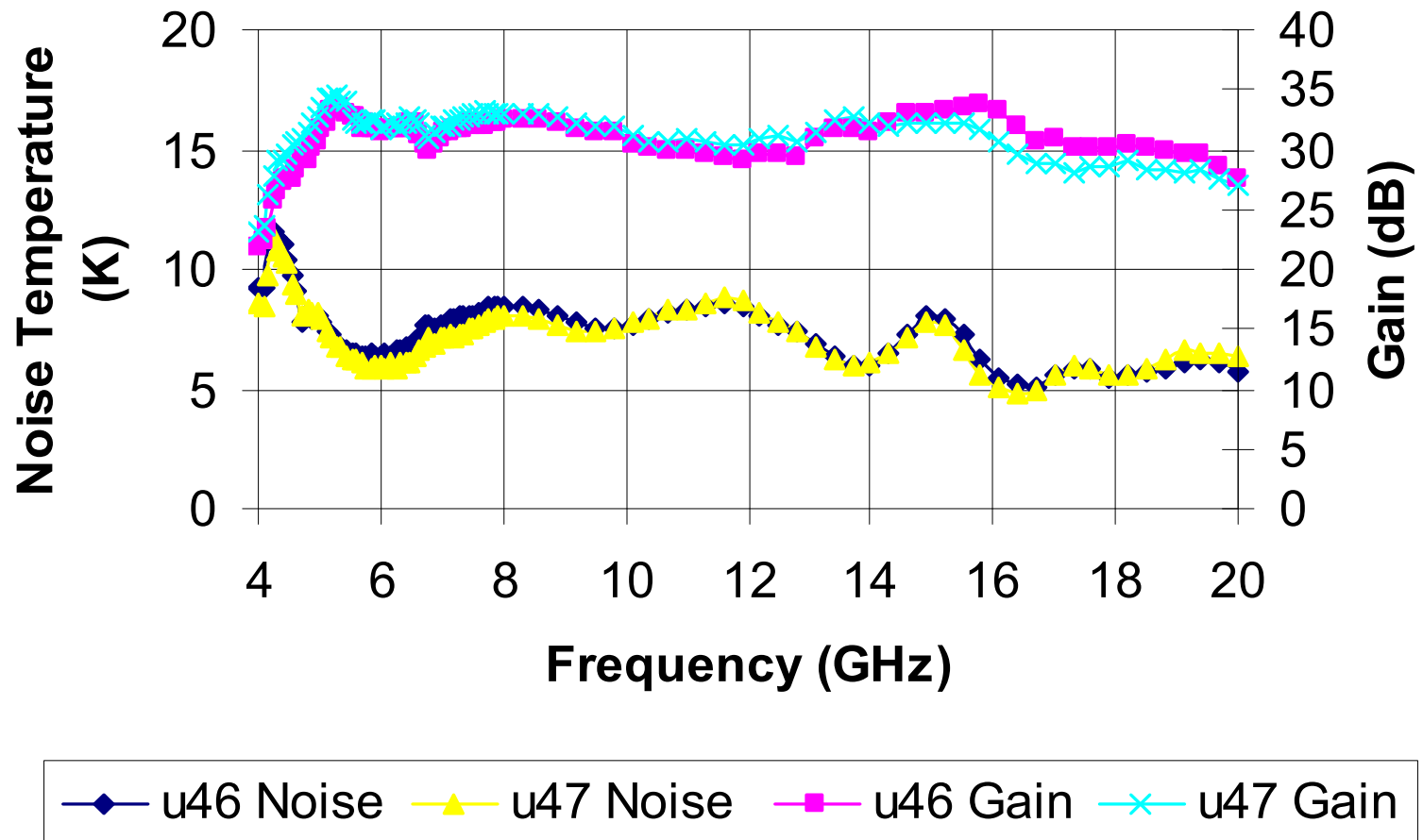


CBI AMPLIFIERS WITH 4080 CRYO3 DEVICE AT 19 K



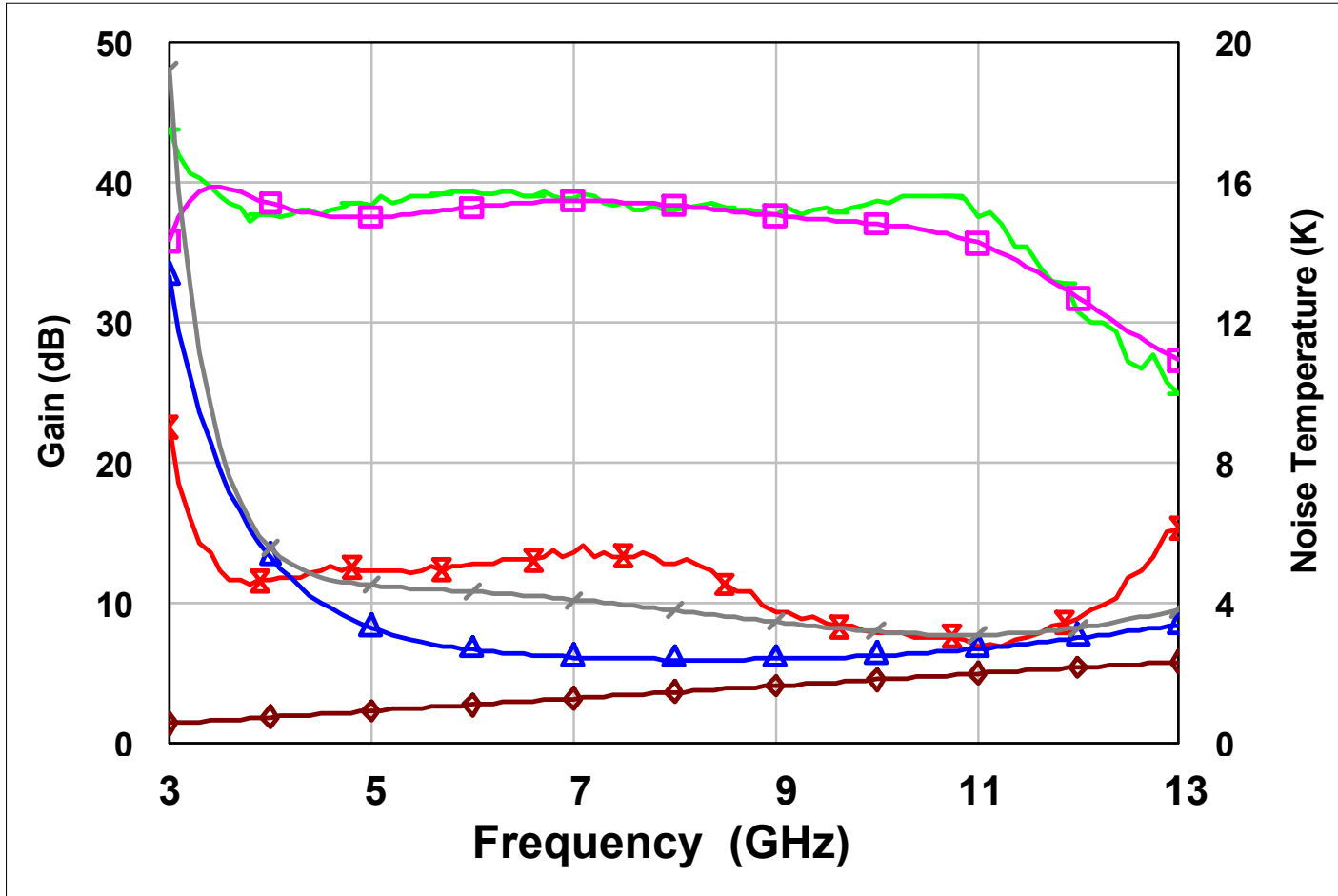


Noise and Gain of 5-20 GHz Amplifier at $T_a=15$ K



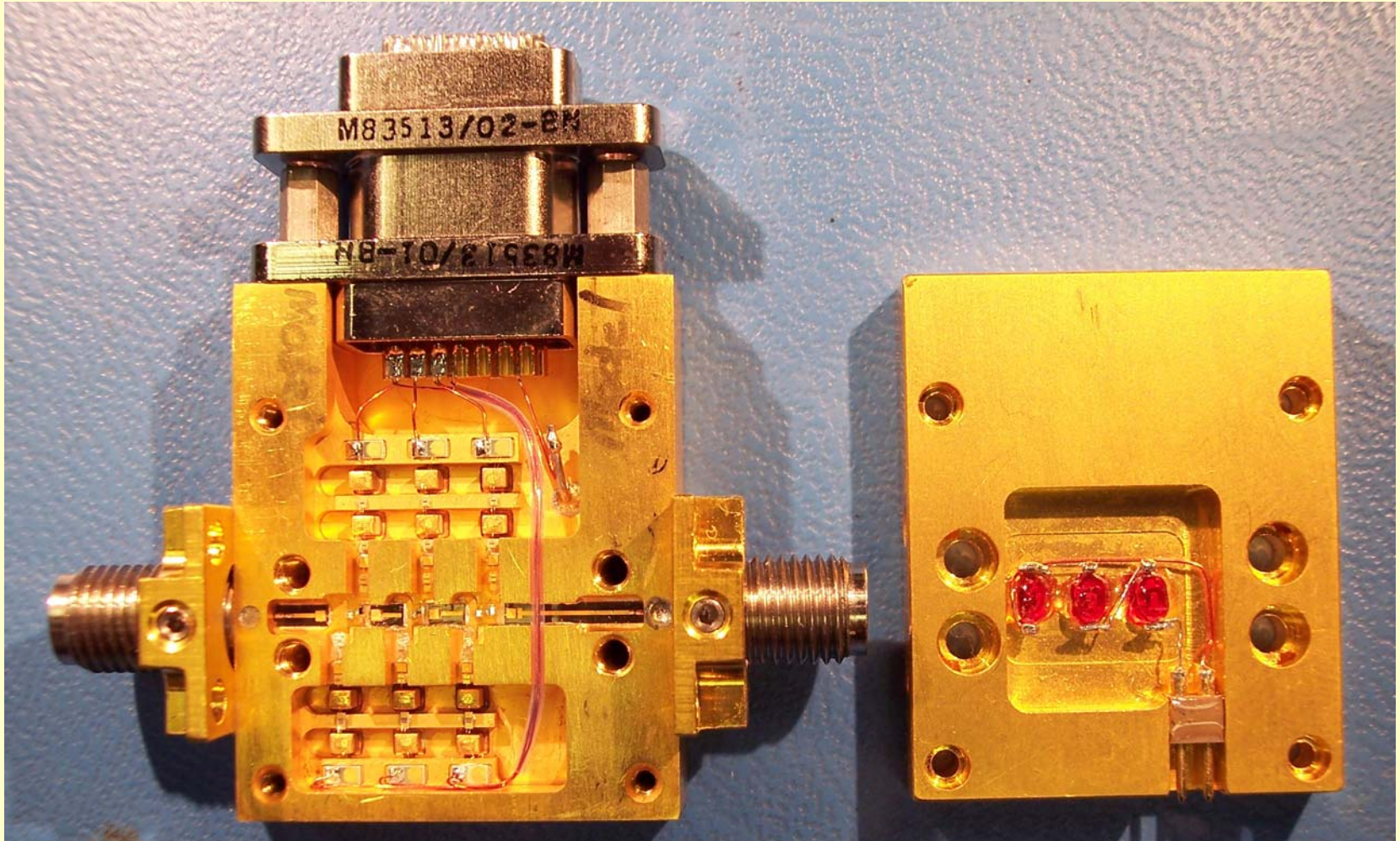


4-12 GHz Amplifier at 15 K



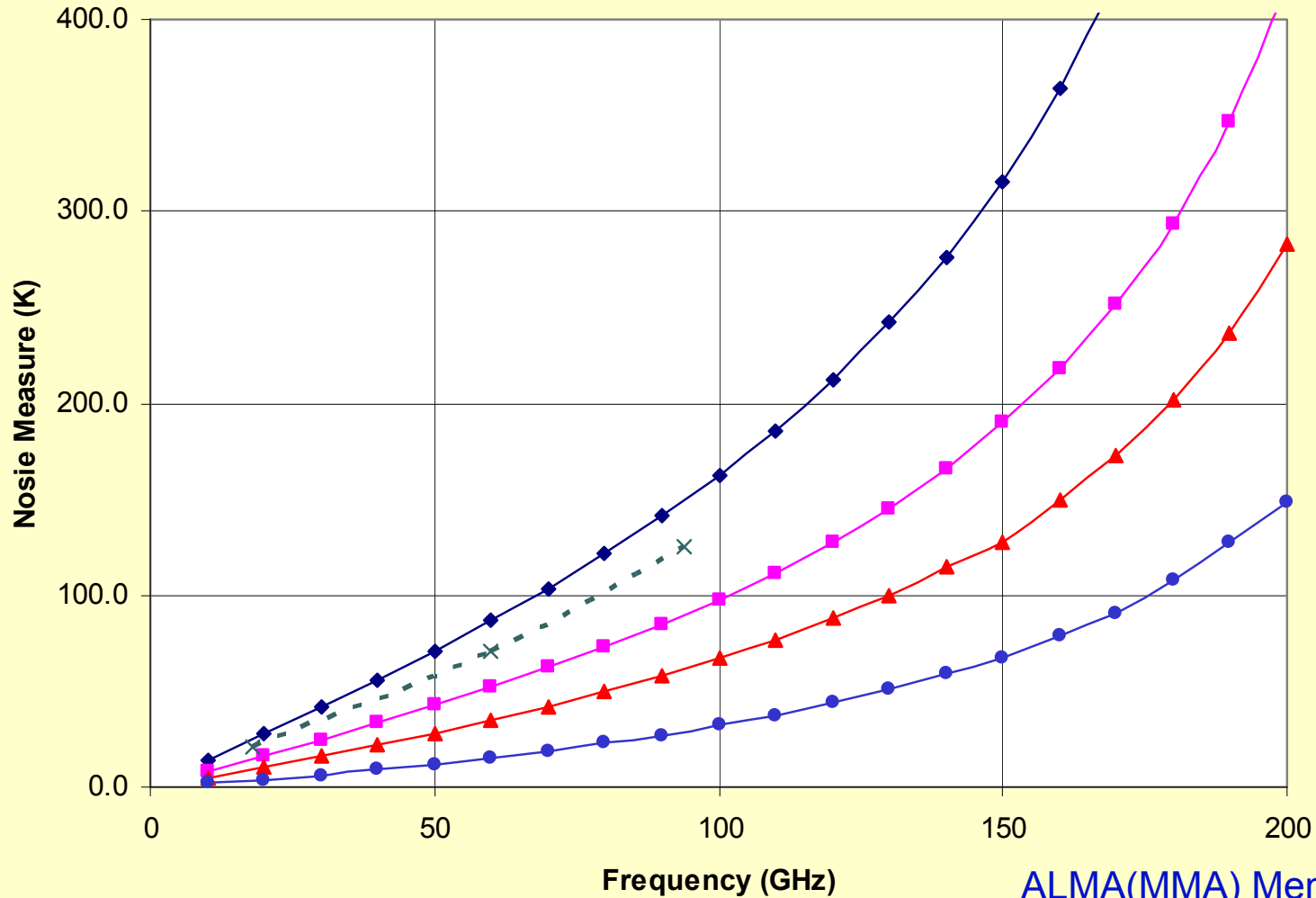
□ Gain (mod) (L) ▲ Tmin Amp. mod. (R) ▾ Noise Temp. meas (R)
— Noise Temp. mod. (R) ◆ Tmin Dev. mod. (R) — Gain. meas. (L)

4-12 GHz Amplifier

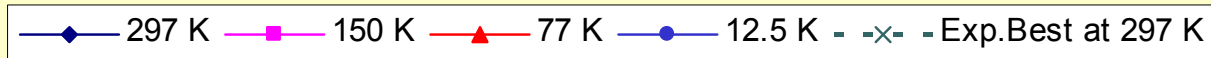




M_{\min} Prediction (1991) and State of the Art (2008)

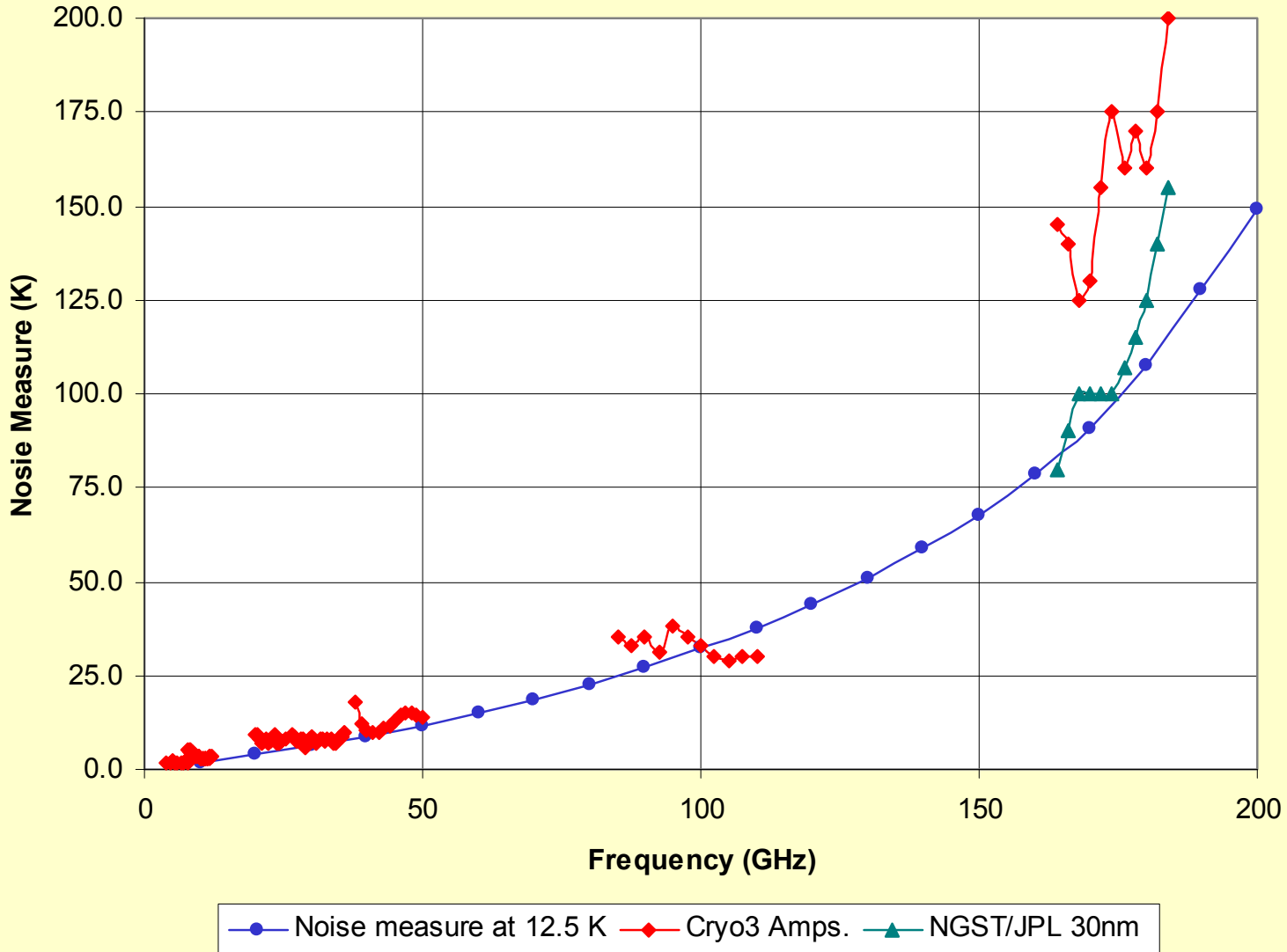


ALMA(MMA) Memo #67,1991





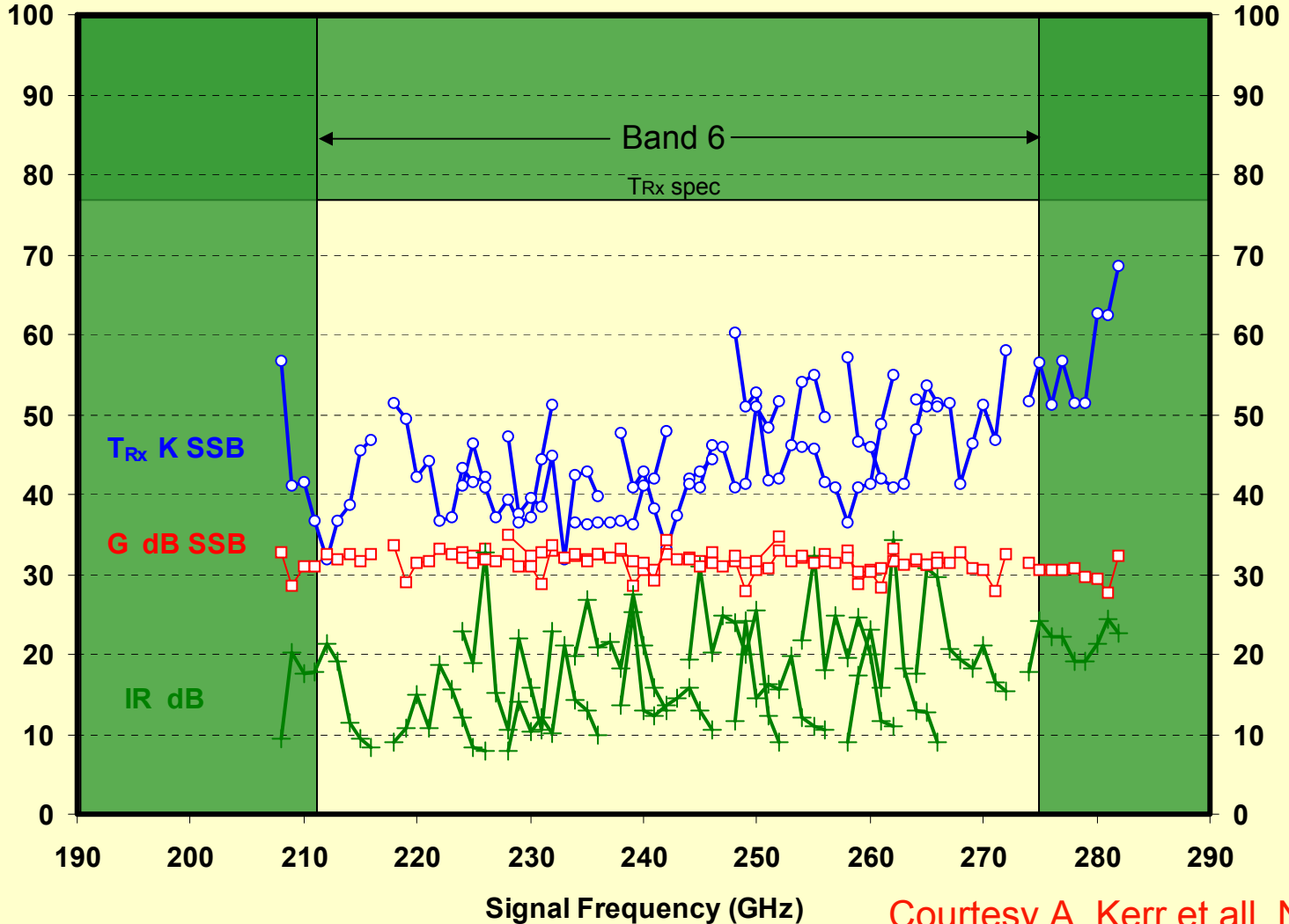
M_{\min} Prediction (1991) and State of the Art (2008)





ALMA BAND#6 RECEIVER

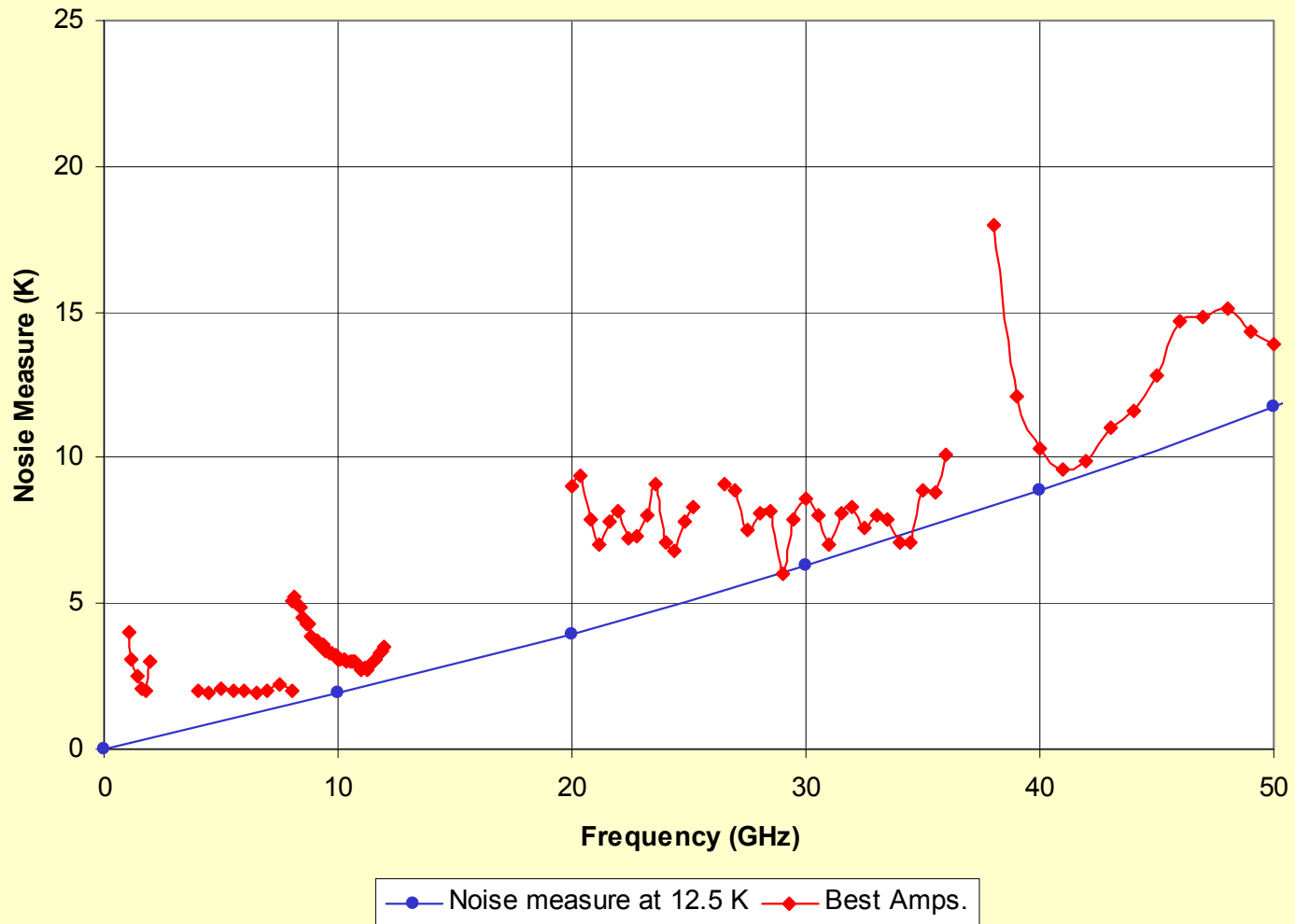
LO: 220-270 GHz in 10 GHz steps



Courtesy A. Kerr et al, NRAO



M_{\min} Prediction (1991) and State of the Art (2008)

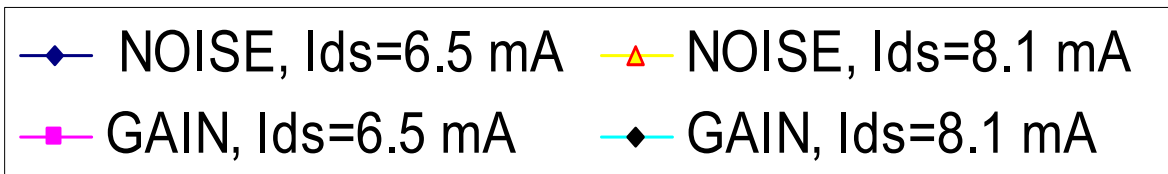
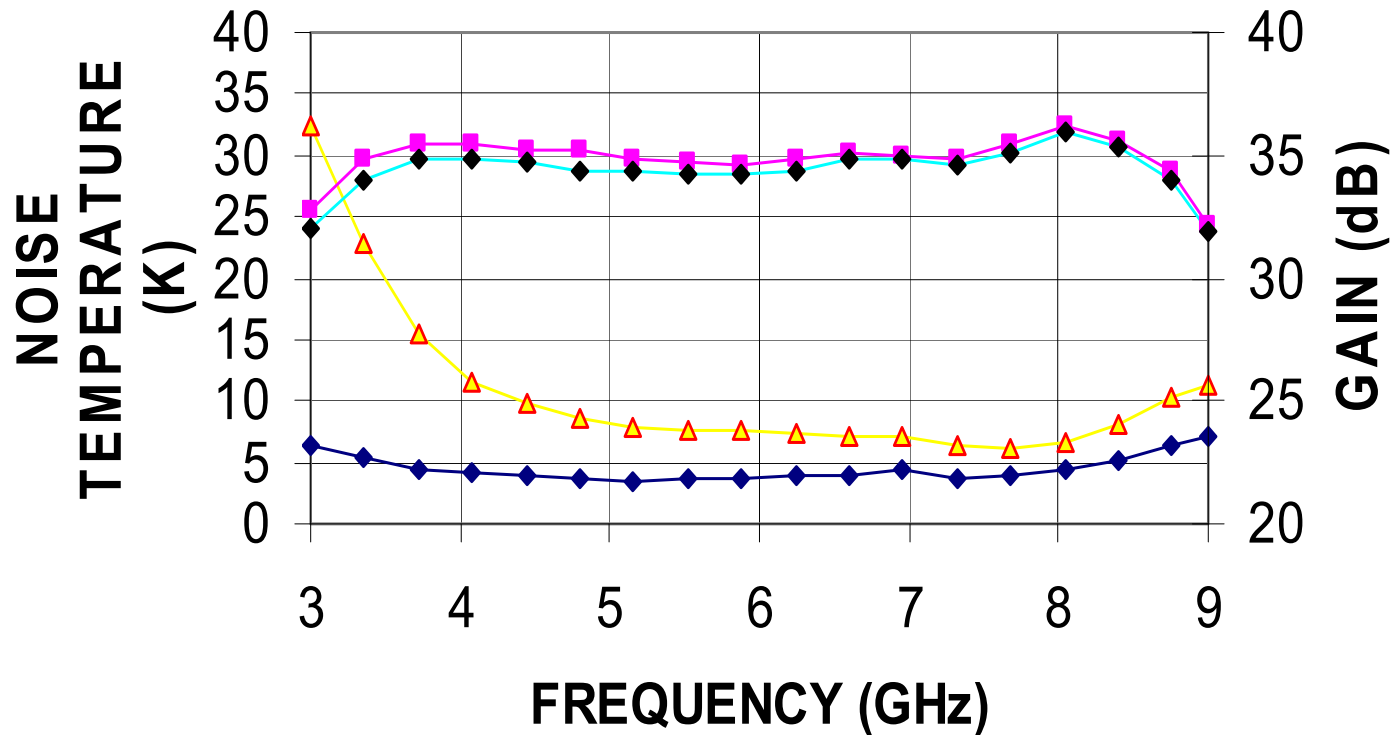




Questions Still Open:

- Dependence of T_d on device structure and properties of electron transport in the channel is not known
- 300 μm wide InP HFET's do not behave as expected from scaling (this applies to all the discrete wafers evaluated at NRAO)
- 200 μm from cryo3 wafer exhibit a very strong dependence of noise on drain voltage at L, S and C bands
- 80 and 60 μm wide devices from cryo3 4044-041 wafer exhibit (sometimes) dc instability which seems to be related to device layout

4_8 GHz AMPLIFIER AT 15 K





Is there a new low noise device just around the corner ?

Possible Future Technology: **InAs/AlSb HFET**

Advantages: very high μ , and $v_s \rightarrow$ high g_m

Disadvantages: impact ionization, high gate leakage currents

State-of-the-art: $f_t \approx 160$ GHz

$T_e \approx 180$ K at 32 GHz and $T_a = 297$ K

For cryo3 devices: $f_t > 180$ GHz

$T_e \approx 80$ K at 32 GHz and $T_a = 297$ K

$T_e \approx 8$ K at 32 GHz and $T_a = 18$ K



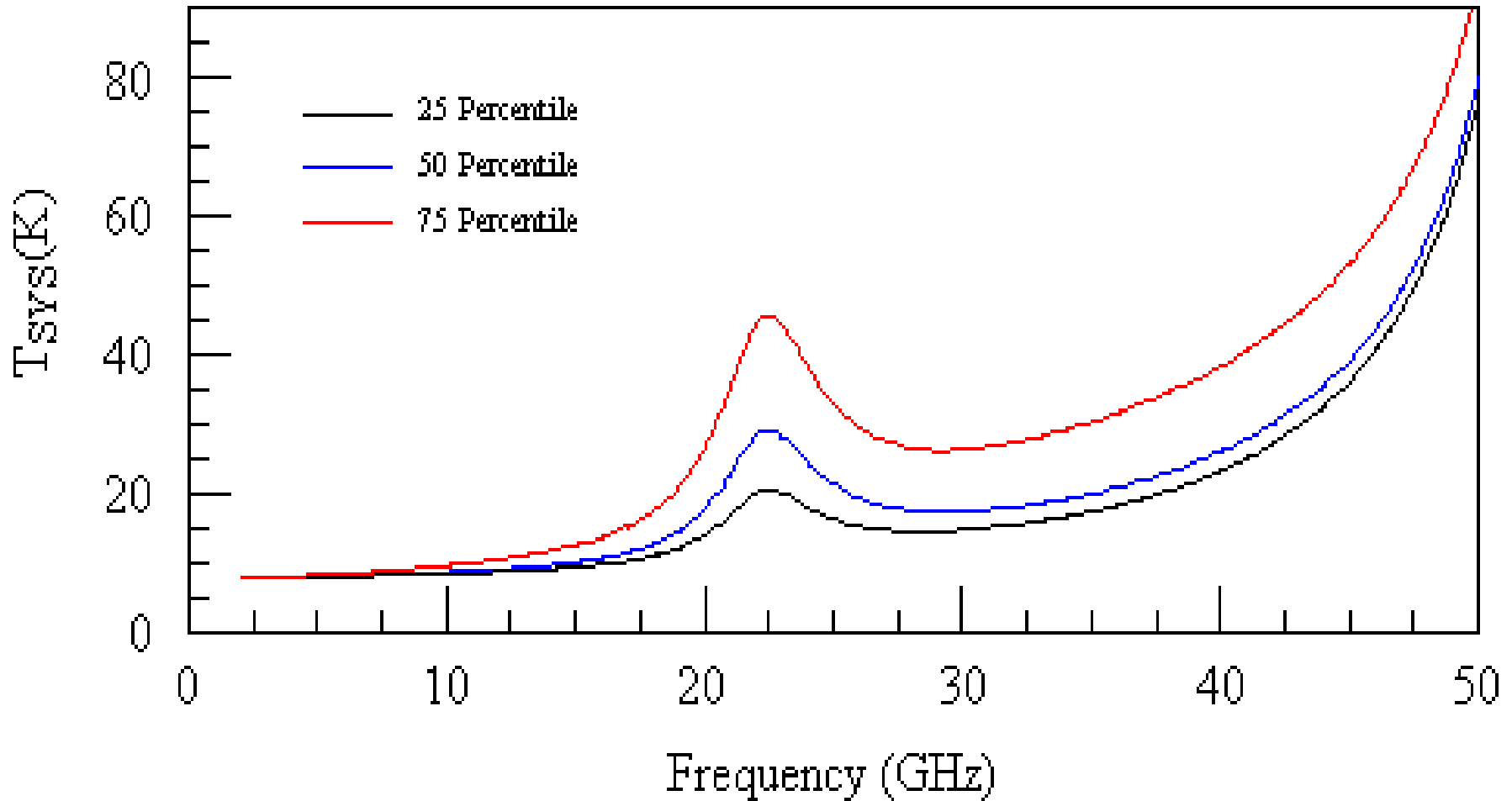
Rick's Performance Metric for an Array

$$FOM = FOV \times B \times \left(\frac{A_{eff}}{T_{sys}} \right)^2$$

$$FOM_M = B \times \frac{A_{eff} n}{T_{sys}^2}$$



GBT T_{sys} at Zenith Except Receiver



Source: GBT/Planning Observations/R.Maddalena



To Cool or Not to Cool

Rule of thumb for amplifiers:

$$T_n(77K) \approx \sqrt{5} \times T_n(15K)$$

$$T_n(297K) \approx 10 \times T_n(15K)$$

For 1-2 GHz:

$$T_S(15) = 15K$$

$$T_S(297) = 40K$$

$$T_n = 3K$$

$$T_n = 28K$$



Wide Band Receivers

- Wide band amplifier: $T_{\text{nav}} = M_{\text{min}}(f_{\text{max}})$
- Wide band feeds: wire-like (lossy)
- Matching of wideband feeds to wide band amplifiers will always produce a structure in the baseline and degrade the noise performance